

Standard Fail Data Log Format for Yield Learning Discussion

Focused discussion at SEMICON West 2008



You are cordially invited to the STDF data log format standardization meeting to be held on the 15th of July from 9:30AM-12:00 (noon), at the Moscone Center, North Hall, room 111 in San Francisco. This meeting is part of the series of open communication meetings to update the industry on the standardization activities.

At the SEMICON West meeting we will present the status of activities in the working groups and our plans going forward. In particular we will present the final version of the scan fail datalog and provide the data model details for the memory fail datalog format. We will also have discussions on the deployment of the scan fail datalog in the industry. Your input and active participation is needed to ensure that the format meets the needs of a broad user base and can become true standard.

We look forward to your participation in establishing a standard that will help you improve time-to-yield.

For more information on STDF [click here](#).

Date, Time and Location

July 15, 2008
9:30AM-12:00 (noon)
Moscone Center
North Hall
Room 111
San Francisco, California

SEMICON West show information

Registration

RSVP to [Ajay Khoche](#)
(408) 864-5123

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